

Features

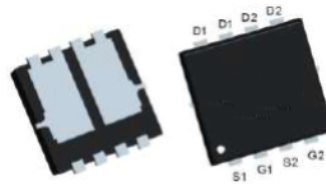
- N+P Channel
- Enhancement mode
- Low on-resistance
- Switching and High efficiency
- Pb-free lead plating; RoHS compliant

Application

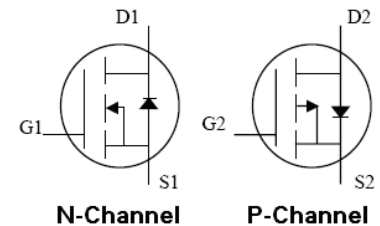
- High battery density grooved N+P dual channel MOSFET
- Synchronous step-down converter applications
- Excellent R_{DS(on)} and gate charge

Product Summary


V_{DS}	30	-30	V
$R_{DS(on),TYP}@ V_{GS}=\pm 10V$	15	24	mΩ
$R_{DS(on),TYP}@ V_{GS}=\pm 4.5V$	23	40	mΩ
I_D	25	-24	A



DFN3.3*3.3-8


N-Channel
P-Channel
Maximum ratings, at $T_A = 25^\circ\text{C}$, unless otherwise specified

Symbol	Parameter	Rating		Unit	
		NMOS	PMOS		
$V_{(BR)DSS}$	Drain-Source breakdown voltage	30	-30	V	
V_{GS}	Gate-Source voltage	± 20	± 20	V	
I_S	Diode continuous forward current	$T_C = 25^\circ\text{C}$	25	-24	A
I_D	Continuous drain current @ $V_{GS} = \pm 10V$	$T_C = 25^\circ\text{C}$	25	-24	A
		$T_C = 100^\circ\text{C}$	16	-15	A
I_{DM}	Pulse drain current tested ①	$T_C = 25^\circ\text{C}$	100	-96	A
I_{DSM}	Continuous drain current @ $V_{GS} = \pm 10V$	$T_A = 25^\circ\text{C}$	11	-9	A
		$T_A = 70^\circ\text{C}$	9	-7	A
EAS	Avalanche energy, single pulsed ②		15	33	mJ
P_D	Maximum power dissipation	$T_C = 25^\circ\text{C}$	14	20	W
P_{DSM}	Maximum power dissipation ③	$T_A = 25^\circ\text{C}$	2.8	2.8	W
T_{STG}, T_J	Storage and junction temperature range		-55 to 150	-55 to 150	$^\circ\text{C}$

Thermal Characteristics

Symbol	Parameter	Typical		Unit
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case	9	6.2	$^\circ\text{C/W}$
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	45		$^\circ\text{C/W}$

N-Channel Electrical Characteristics

Symbol	Parameter	Condition	Min	Typ	Max	Unit
Static Electrical Characteristics @ T_J = 25°C (unless otherwise stated)						
V _{(BR)DSS}	Drain-Source Breakdown Voltage	V _{GS} =0V, I _D =250μA	30	--	--	V
I _{DSS}	Zero Gate Voltage Drain Current(T _J =25°C)	V _{DS} =30V, V _{GS} =0V	--	--	1	μA
	Zero Gate Voltage Drain Current(T _J =125°C)	V _{DS} =30V, V _{GS} =0V	--	--	100	μA
I _{GSS}	Gate-Body Leakage Current	V _{GS} =±20V, V _{DS} =0V	--	--	±100	nA
V _{GS(TH)}	Gate Threshold Voltage	V _{DS} =V _{GS} , I _D =250μA	1.3	1.9	2.4	V
R _{DS(ON)}	Drain-Source On-State Resistance ④	V _{GS} =10V, I _D =8A	--	15	21	mΩ
		V _{GS} =4.5V, I _D =6A	--	23	32	mΩ
Dynamic Electrical Characteristics @ T_J = 25°C (unless otherwise stated)						
C _{iss}	Input Capacitance	V _{DS} =15V, V _{GS} =0V, f=1MHz	350	455	550	pF
C _{oss}	Output Capacitance		--	75	130	pF
C _{rss}	Reverse Transfer Capacitance		--	55	110	pF
R _g	Gate Resistance	f=1MHz	--	5.4	--	Ω
Q _g	Total Gate Charge	V _{DS} =15V, I _D =8A, V _{GS} =10V	--	11.3	--	nC
Q _{gs}	Gate Source Charge		--	3	--	nC
Q _{gd}	Gate Drain Charge		--	4.3	--	nC
Switching Characteristics						
t _{d(on)}	Turn on Delay Time	V _{DD} =15V, I _D =8A, R _G =3Ω, V _{GS} =10V	--	7	--	ns
t _r	Turn on Rise Time		--	10	--	ns
t _{d(off)}	Turn Off Delay Time		--	22	--	ns
t _f	Turn Off Fall Time		--	7	--	ns
Source Drain Diode Characteristics						
V _{SD}	Forward on voltage	I _{SD} =8A, V _{GS} =0V	--	0.9	1.2	V
t _{rr}	Reverse Recovery Time	T _J =25°C, I _{sd} =8A, V _{GS} =0V	--	9.5	--	ns
Q _{rr}	Reverse Recovery Charge	di/dt=500A/μs	--	11.8	--	nC

P-Channel Electrical Characteristics

Symbol	Parameter	Condition	Min	Typ	Max	Unit
Static Electrical Characteristics @ T_J = 25°C (unless otherwise stated)						
V _{(BR)DSS}	Drain-Source Breakdown Voltage	V _{GS} =0V, I _D =-250μA	-30	--	--	V
I _{DSS}	Zero Gate Voltage Drain Current(T _J =25°C)	V _{DS} =-30V, V _{GS} =0V	--	--	-1	μA
	Zero Gate Voltage Drain Current(T _J =125°C)	V _{DS} =-30V, V _{GS} =0V	--	--	-100	μA
I _{GSS}	Gate-Body Leakage Current	V _{GS} =±20V, V _{DS} =0V	--	--	±100	nA
V _{GS(TH)}	Gate Threshold Voltage	V _{DS} =V _{GS} , I _D =-250μA	-1.3	-1.9	-2.4	V
R _{DS(ON)}	Drain-Source On-State Resistance ④	V _{GS} =-10V, I _D =-8A	--	24	34	mΩ
		V _{GS} =-4.5V, I _D =-6A	--	40	57	mΩ
Dynamic Electrical Characteristics @ T_J = 25°C (unless otherwise stated)						
C _{iss}	Input Capacitance	V _{DS} =-15V, V _{GS} =0V, f=1MHz	760	865	960	pF
C _{oss}	Output Capacitance		60	140	200	pF
C _{rss}	Reverse Transfer Capacitance		30	95	150	pF
R _g	Gate Resistance	f=1MHz	--	12.3	--	Ω
Q _g	Total Gate Charge	V _{DS} =-15V, I _D =-8A, V _{GS} =-10V	--	19	--	nC
Q _{gs}	Gate Source Charge		--	4.3	--	nC
Q _{gd}	Gate Drain Charge		--	6.5	--	nC
Switching Characteristics						
t _{d(on)}	Turn on Delay Time	V _{DD} =-15V, I _D =-8A, R _G =3Ω, V _{GS} =-10V	--	6	--	ns
t _r	Turn on Rise Time		--	5	--	ns
t _{d(off)}	Turn Off Delay Time		-	25	--	ns
t _f	Turn Off Fall Time		--	7	--	ns
Source Drain Diode Characteristics						
V _{SD}	Forward on voltage	I _{SD} =-8A, V _{GS} =0V	--	-0.9	-1.2	V
t _{rr}	Reverse Recovery Time	T _J =25°C, I _{SD} =-8A, V _{GS} =0V	--	7	--	ns
Q _{rr}	Reverse Recovery Charge	di/dt=-500A/μs	--	6.3	--	nC

N-Channel Typical Characteristics

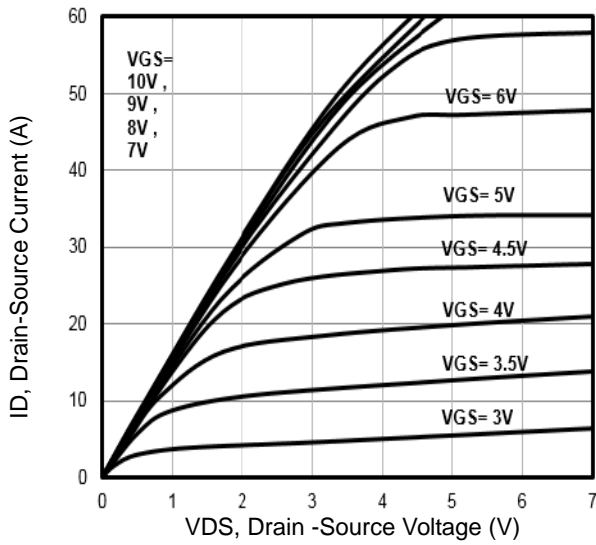


Fig1. Typical Output Characteristics

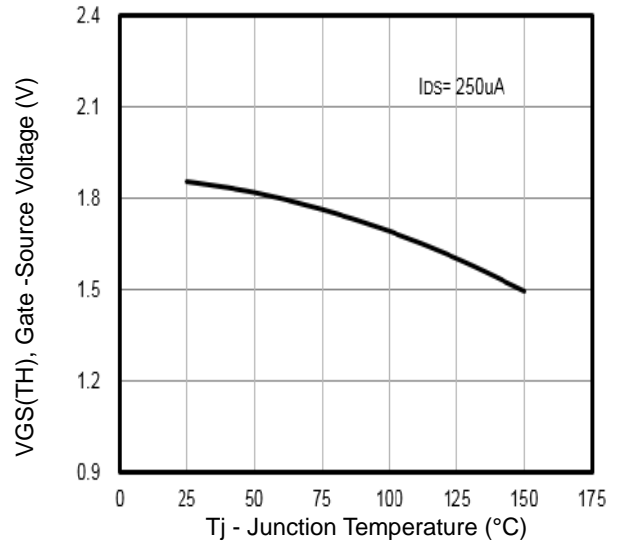


Fig2. $V_{GS(TH)}$ Gate-Source Voltage Vs. T_j

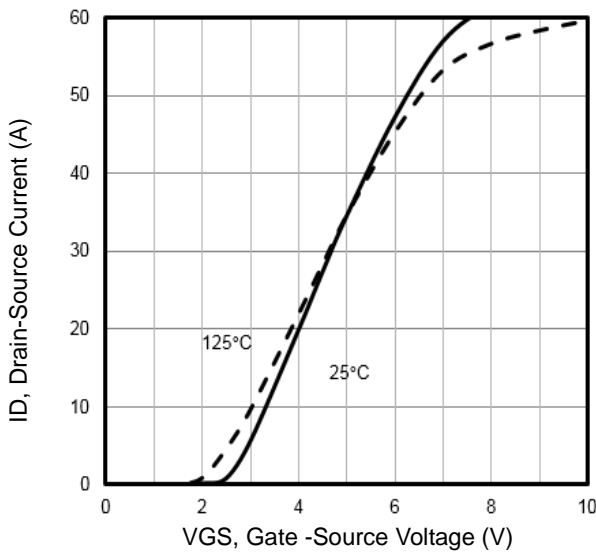


Fig3. Typical Transfer Characteristics

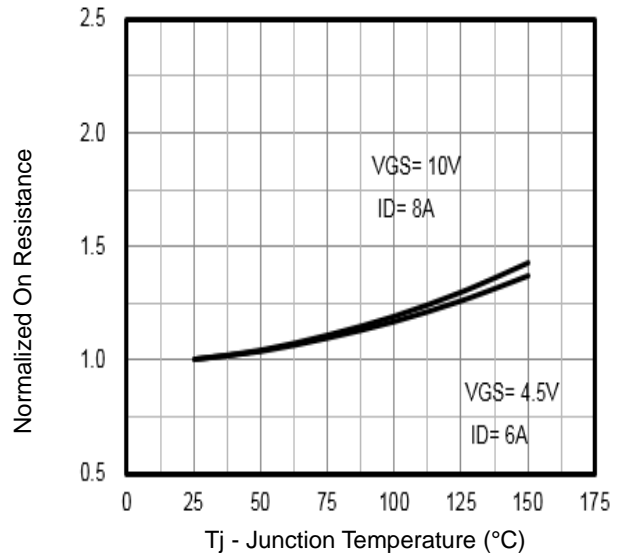


Fig4. Normalized On-Resistance Vs. T_j

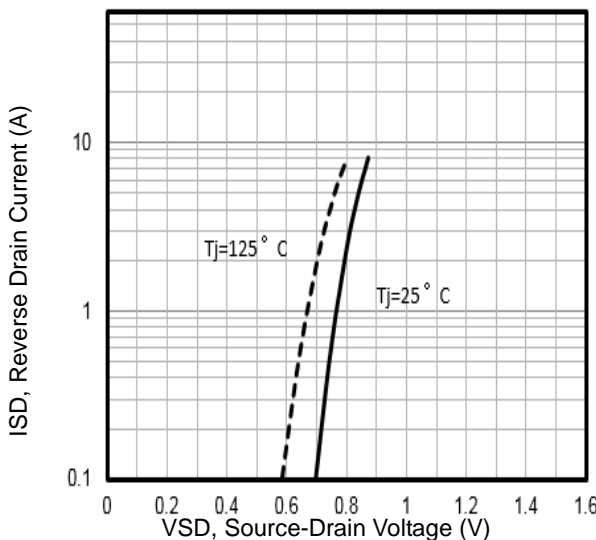


Fig5. Typical Source-Drain Diode Forward Voltage

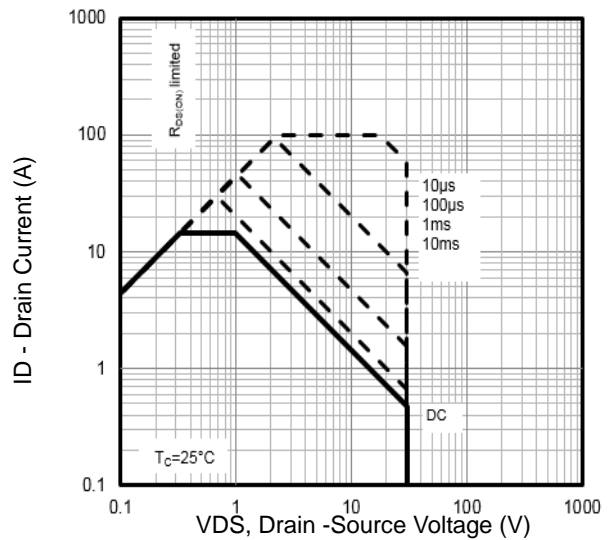


Fig6. Maximum Safe Operating Area

N-Channel Typical Characteristics

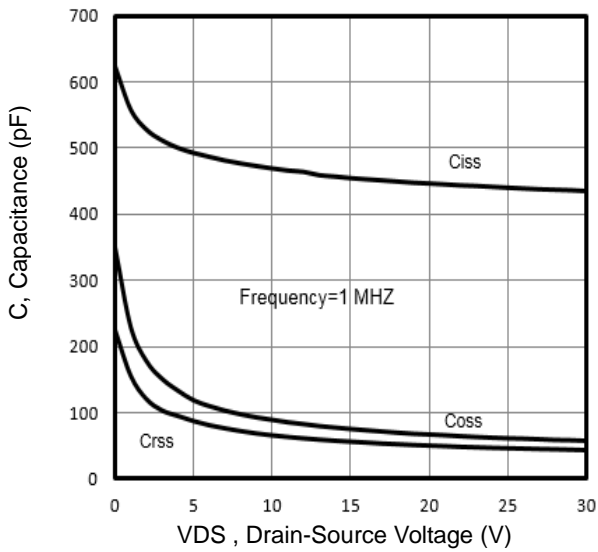


Fig7. Typical Capacitance Vs.Drain-Source Voltage

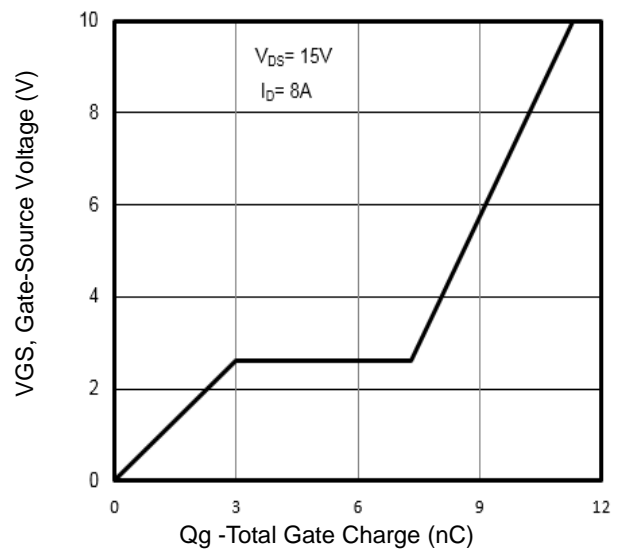


Fig8. Typical Gate Charge Vs.Gate-Source Voltage

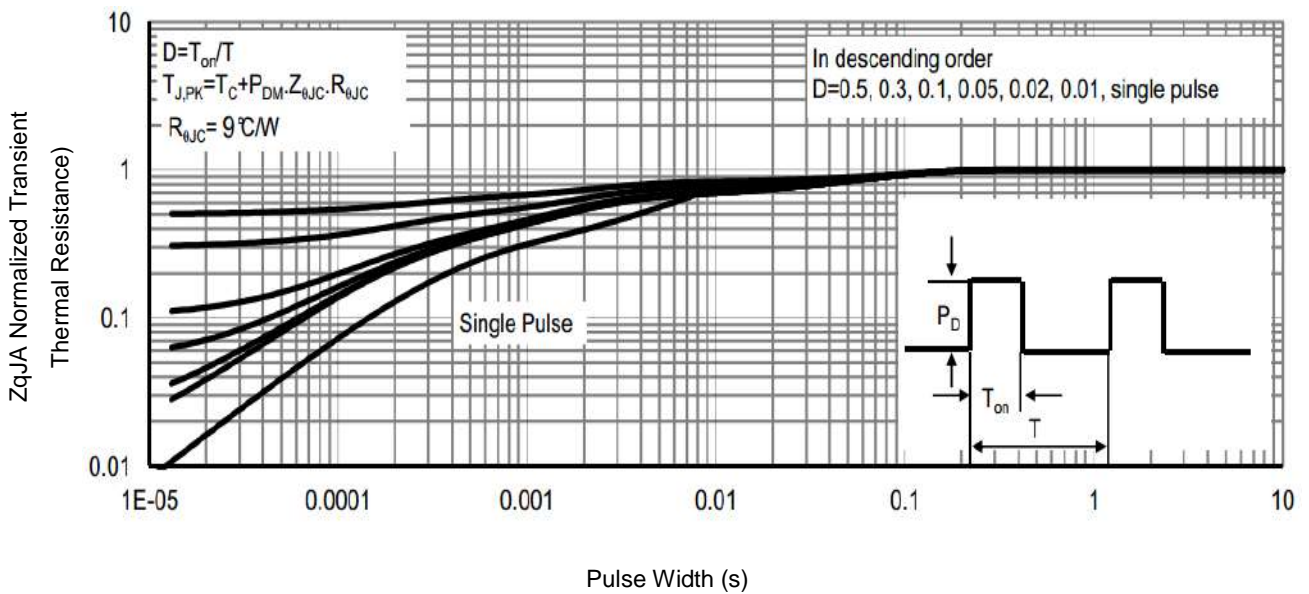


Fig 9 .Normalized Maximum Transient Thermal Impedance

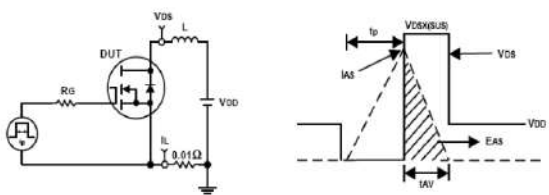


Fig10. Unclamped Inductive Test Circuit and waveforms

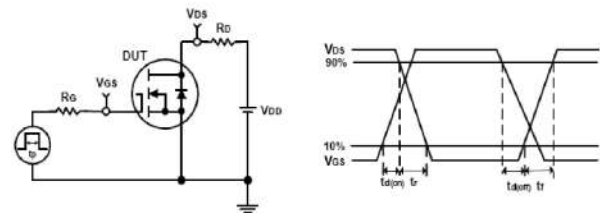


Fig11. Switching Time Test Circuit and waveforms

P-Channel Typical Characteristics

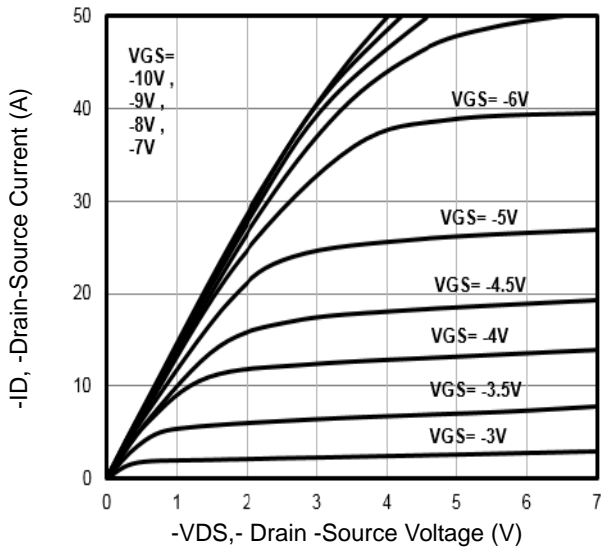


Fig1. Typical Output Characteristics

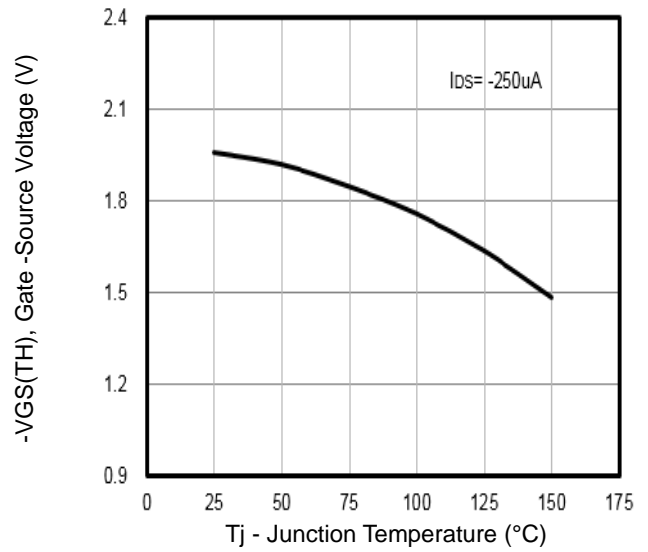


Fig2. $-V_{GS(TH)}$ Gate -Source Voltage Vs. T_j

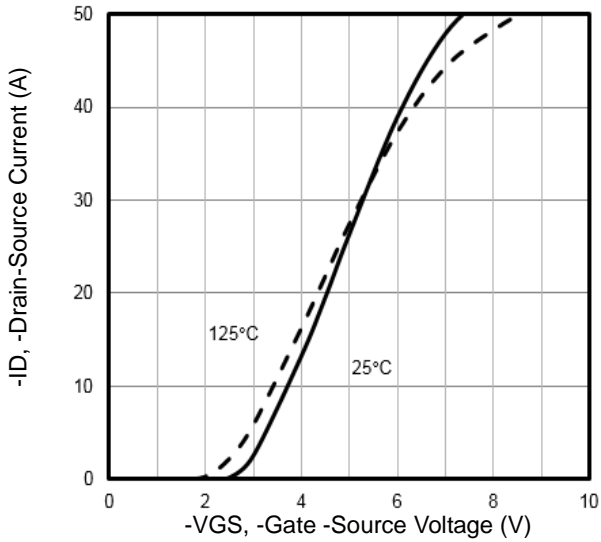


Fig3. Typical Transfer Characteristics

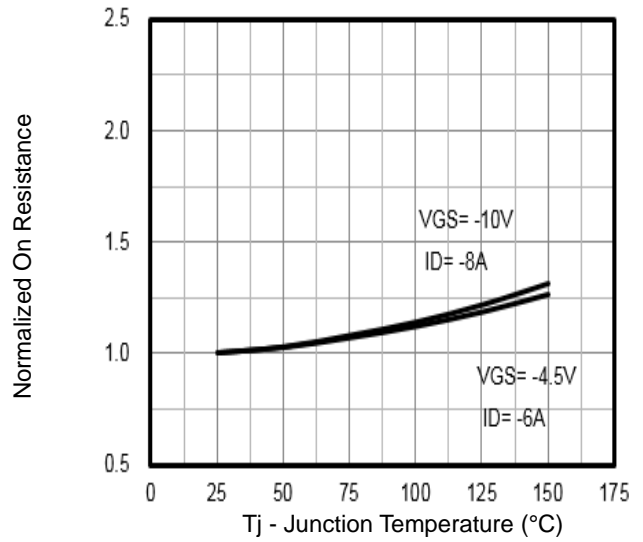


Fig4. Normalized On-Resistance Vs. T_j

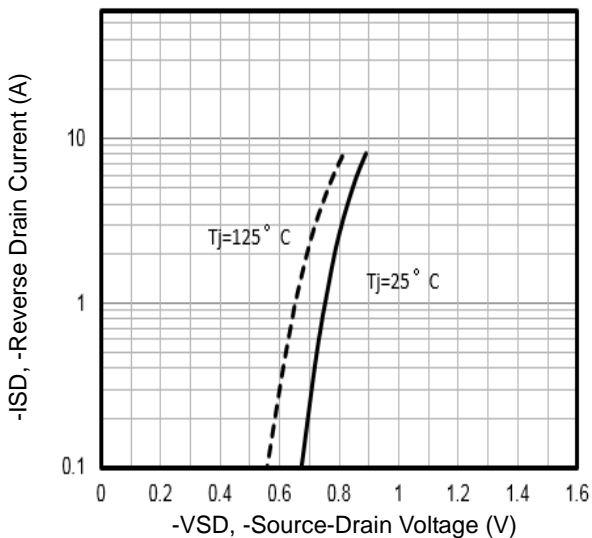


Fig5. Typical Source-Drain Diode Forward Voltage

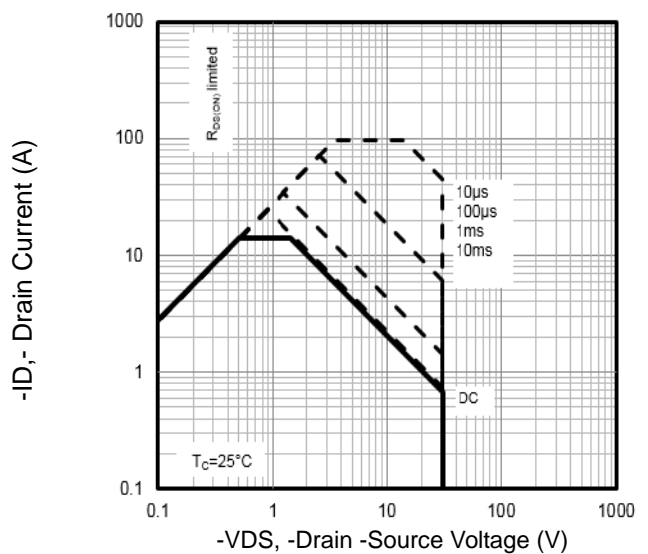


Fig6. Maximum Safe Operating Area

P-Channel Typical Characteristics

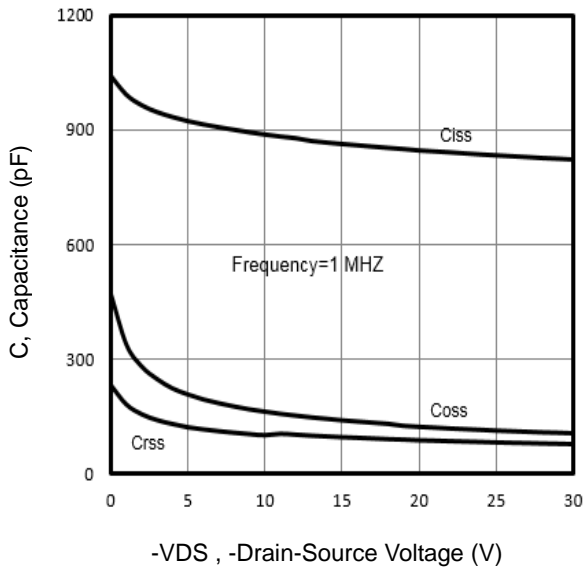


Fig7. Typical Capacitance Vs.Drain-Source Voltage

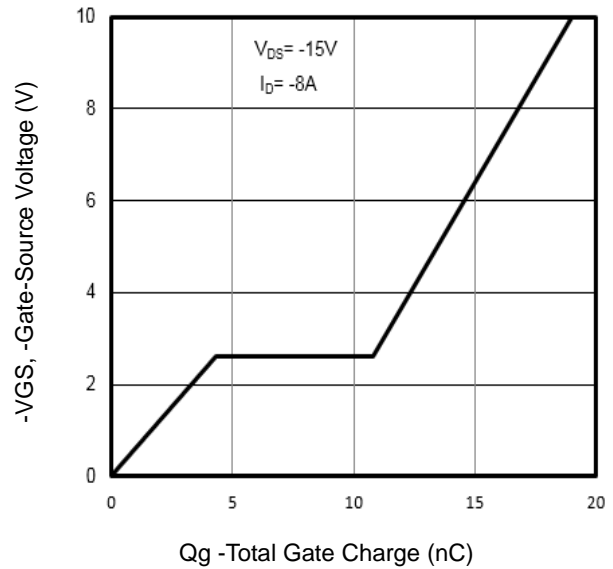


Fig8. Typical Gate Charge Vs.Gate-Source Voltage

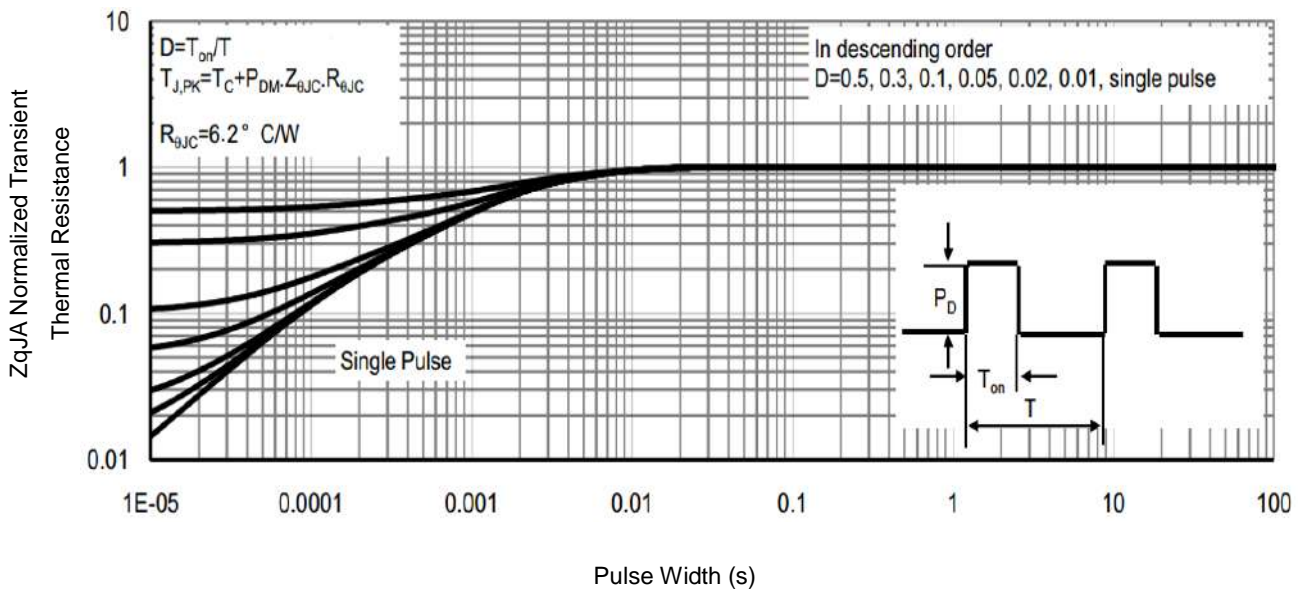


Fig9. Normalized Maximum Transient Thermal Impedance

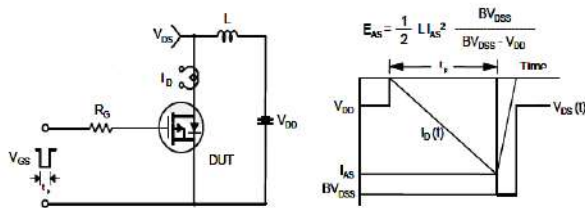


Fig10. Unclamped Inductive Test Circuit and Waveforms

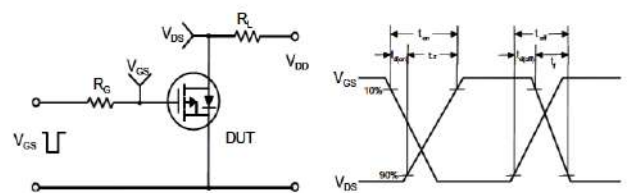
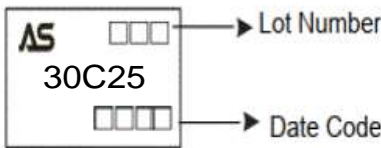


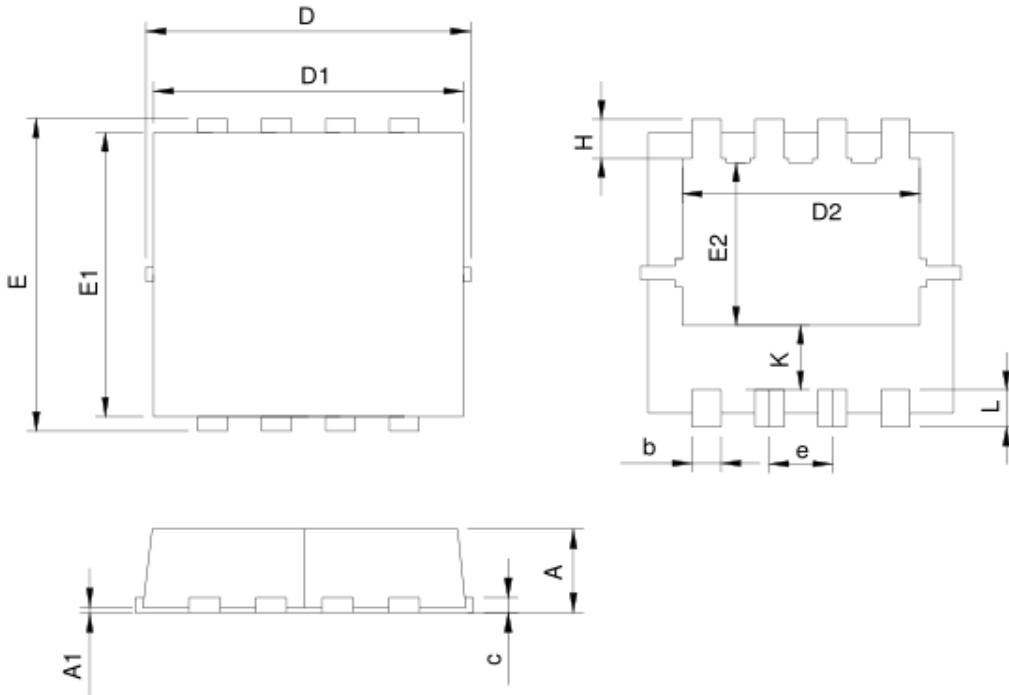
Fig11. Switching Time Test Circuit and waveforms

Ordering and Marking Information

Ordering Device No.	Marking	Package	Packing	Quantity
ASDM30C25E-R	30C25	DFN3.3*3.3-8	Tape&Reel	5000/Reel

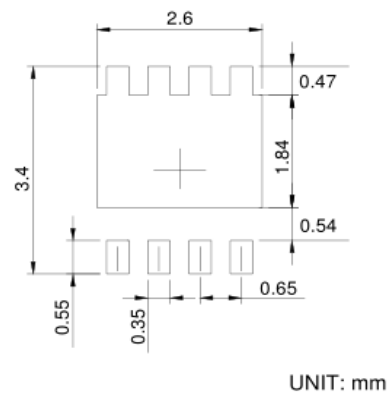
PACKAGE	MARKING
DFN3.3*3.3-8	 <p>AS □□□□ → Lot Number 30C25 □□□□ → Date Code</p>

Dimensions(DFN3.3x3.3-8)



SYMBOL	DFN3.3x3.3-8			
	MILLIMETERS		INCHES	
	MIN.	MAX.	MIN.	MAX.
A	0.70	1.00	0.028	0.039
A1	0.00	0.05	0.000	0.002
b	0.25	0.35	0.010	0.014
c	0.14	0.20	0.006	0.008
D	3.10	3.50	0.122	0.138
D1	3.05	3.25	0.120	0.128
D2	2.35	2.55	0.093	0.100
E	3.10	3.50	0.122	0.138
E1	2.90	3.10	0.114	0.122
E2	1.64	1.84	0.065	0.072
e	0.65 BSC		0.026 BSC	
H	0.32	0.52	0.013	0.020
K	0.59	0.79	0.023	0.031
L	0.25	0.55	0.010	0.022

RECOMMENDED LAND PATTERN



UNIT: mm

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